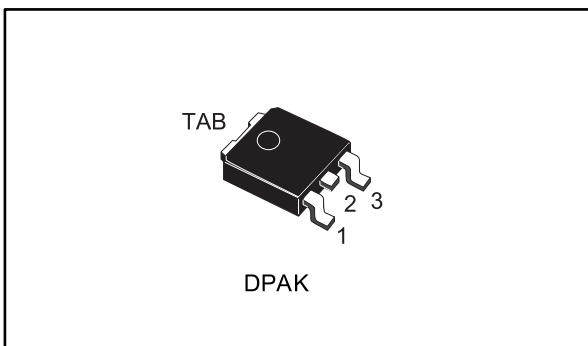
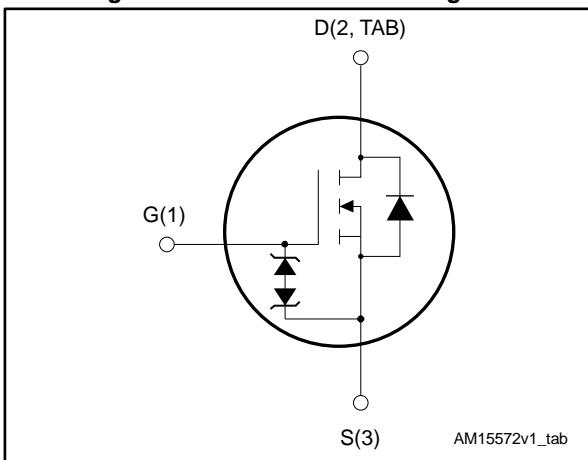


## N-channel 600 V, 0.71 Ω typ., 5.5 A MDmesh™ M2 Power MOSFET in a DPAK package

Datasheet - production data



**Figure 1: Internal schematic diagram**



### Features

Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STD9HN65M2	600 V	0.82 Ω	5.5 A

- Extremely low gate charge
- Excellent output capacitance (C<sub>oss</sub>) profile
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using MDmesh™ M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.

**Table 1: Device summary**

Order code	Marking	Package	Packing
STD9HN65M2	9HN65M2	DPAK	Tape and reel

## Contents

<b>1</b>	<b>Electrical ratings .....</b>	<b>3</b>
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# 1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	5.5	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	3.5	A
$I_{DM}^{(1)}$	Drain current (pulsed)	22	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	60	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(3)}$	MOSFET $dv/dt$ ruggedness	50	V/ns
$T_{stg}$	Storage temperature	- 55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	

**Notes:**

(1) Pulse width limited by safe operating area.

(2)  $I_{SD} \leq 5.5$  A,  $di/dt \leq 400$  A/ $\mu\text{s}$ ;  $V_{DS}$  peak <  $V_{(BR)DSS}$ ,  $V_{DD} = 80\%$   $V_{(BR)DSS}$ .(3)  $V_{DS} \leq 520$  V.

Table 3: Thermal data

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max.	2.08	$^\circ\text{C/W}$
$R_{thj-pcb}^{(1)}$	Thermal resistance junction-pcb max.	50	$^\circ\text{C/W}$

**Notes:**(1) When mounted on a 1-inch<sup>2</sup> FR-4, 2 oz Cu board.

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax}$ )	1.0	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50$ V)	105	mJ

## 2 Electrical characteristics

( $T_C = 25^\circ\text{C}$  unless otherwise specified).

**Table 5: Static**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	650			V
$I_{\text{DSS}}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 650 \text{ V}, T_C = 125^\circ\text{C}$			100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 2.5 \text{ A}$		0.71	0.82	$\Omega$

**Table 6: Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	325	-	pF
$C_{oss}$	Output capacitance		-	16	-	pF
$C_{rss}$	Reverse transfer capacitance		-	0.85	-	pF
$C_{oss \text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{DS} = 0 \text{ V to } 520 \text{ V}, V_{GS} = 0 \text{ V}$	-	109	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}$ open drain	-	5.6	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 520 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}$ (see <i>Figure 15: "Gate charge test circuit"</i> )	-	11.5	-	nC
$Q_{gs}$	Gate-source charge		-	2.5	-	nC
$Q_{gd}$	Gate-drain charge		-	5	-	nC

**Notes:**

<sup>(1)</sup>  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

**Table 7: Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 325 \text{ V}, I_D = 2.5 \text{ A}$ $R_G = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 14: "Switching times test circuit for resistive load"</i> and <i>Figure 19: "Switching time waveform"</i> )	-	7.5	-	ns
$t_r$	Rise time		-	4.6	-	ns
$t_{d(off)}$	Turn-off-delay time		-	24	-	ns
$t_f$	Fall time		-	14.5	-	ns

Table 8: Source drain diode

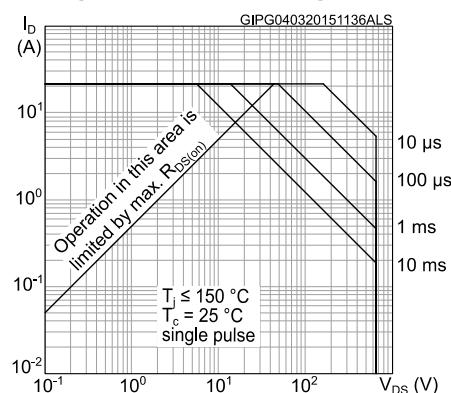
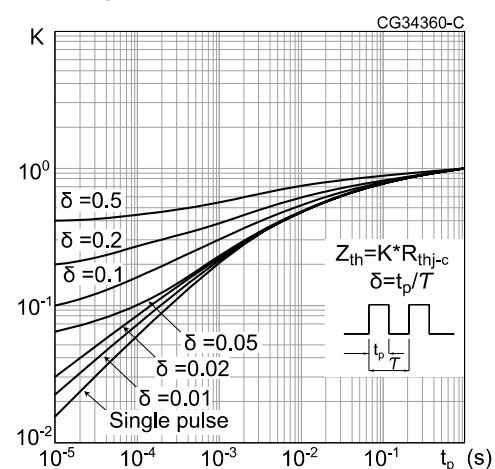
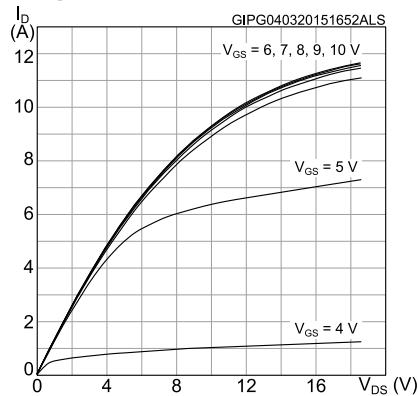
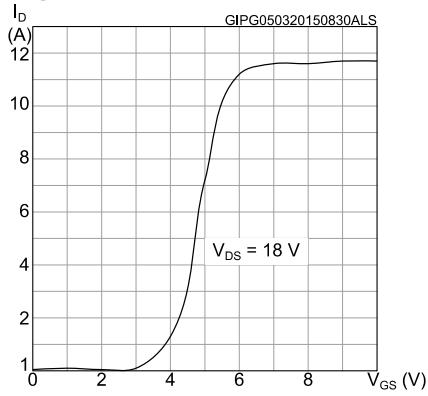
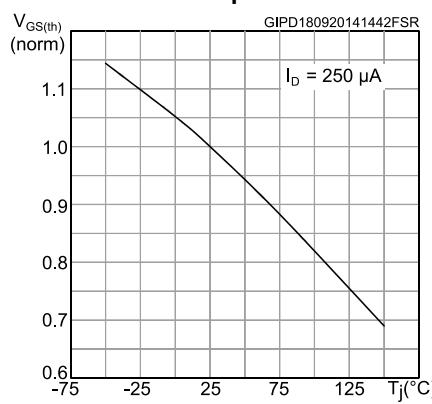
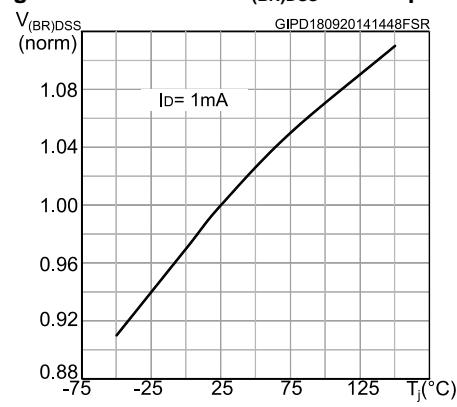
Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current		-		5.5	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		22	A
$V_{SD}^{(2)}$	Forward on voltage	$V_{GS} = 0 \text{ V}$ , $I_{SD} = 5 \text{ A}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 5 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ (see <a href="#">Figure 16: "Test circuit for inductive load switching and diode recovery times"</a> )	-	268		ns
$Q_{rr}$	Reverse recovery charge		-	1.7		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	12.5		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 5 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ , $V_{DD} = 60 \text{ V}$ , $T_j = 150^\circ\text{C}$ (see <a href="#">Figure 16: "Test circuit for inductive load switching and diode recovery times"</a> )	-	408		ns
$Q_{rr}$	Reverse recovery charge		-	2.6		$\mu\text{C}$
$I_{RRM}$	Reverse recovery current		-	13		A

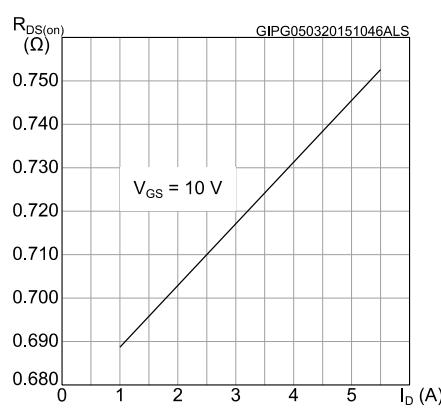
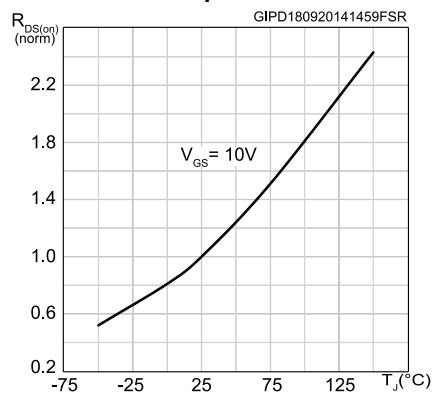
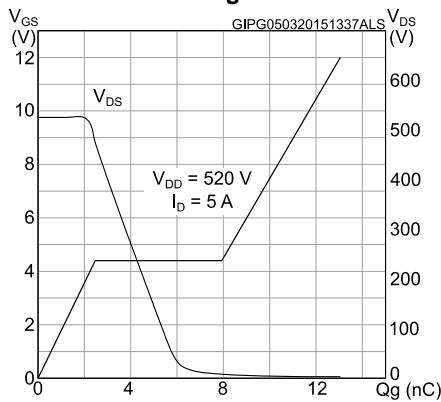
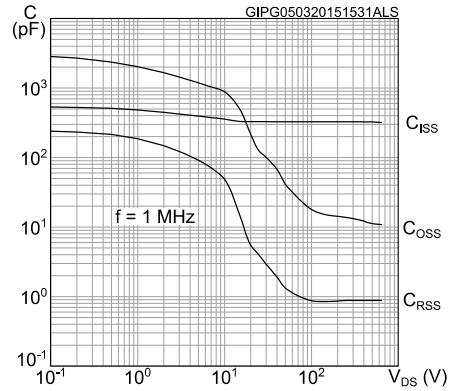
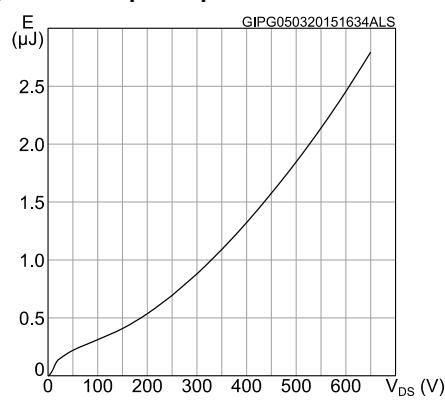
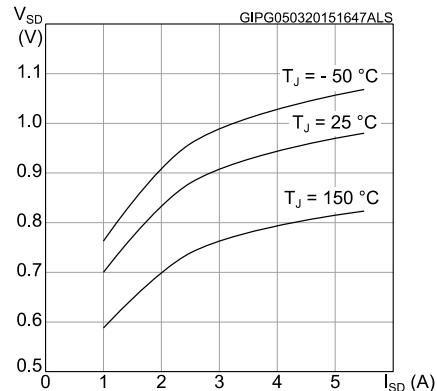
**Notes:**

(1) Pulse width is limited by safe operating area.

(2) Pulse test: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

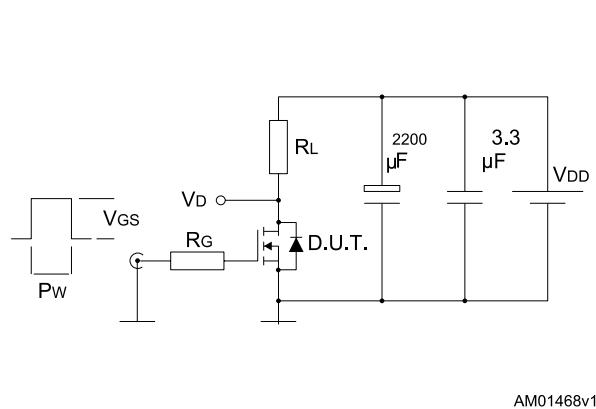
## 2.1 Electrical characteristics (curves)

**Figure 2: Safe operating area****Figure 3: Thermal impedance****Figure 4: Output characteristics****Figure 5: Transfer characteristics****Figure 6: Normalized gate threshold voltage vs. temperature****Figure 7: Normalized V(BR)DSS vs. temperature**

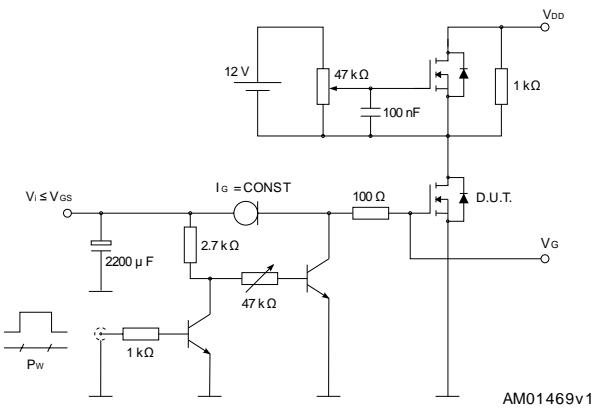
**Figure 8: Static drain-source on-resistance****Figure 9: Normalized on-resistance vs. temperature****Figure 10: Gate charge vs. gate-source voltage****Figure 11: Capacitance variations****Figure 12: Output capacitance stored energy****Figure 13: Source- drain diode forward characteristics**

### 3 Test circuits

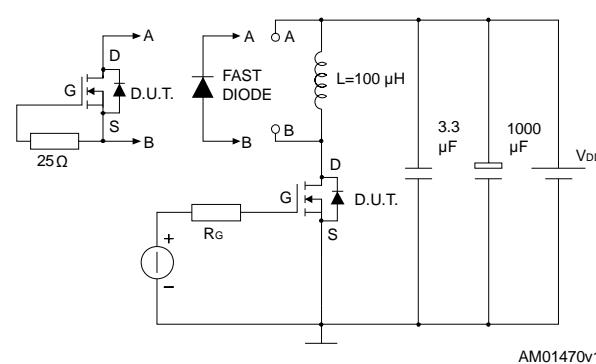
**Figure 14: Switching times test circuit for resistive load**



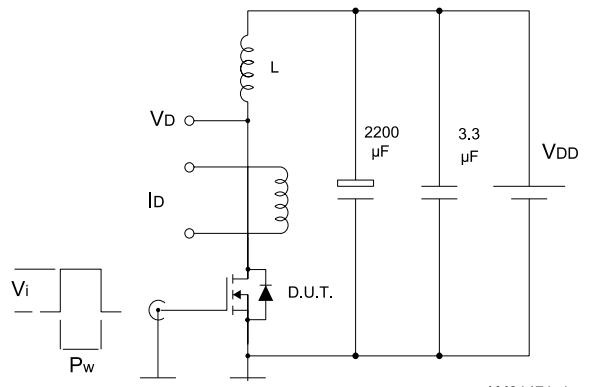
**Figure 15: Gate charge test circuit**



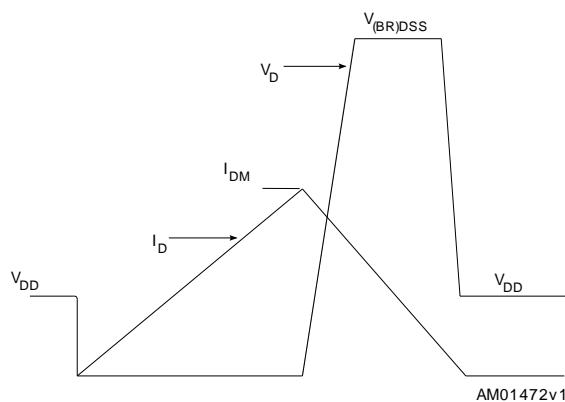
**Figure 16: Test circuit for inductive load switching and diode recovery times**



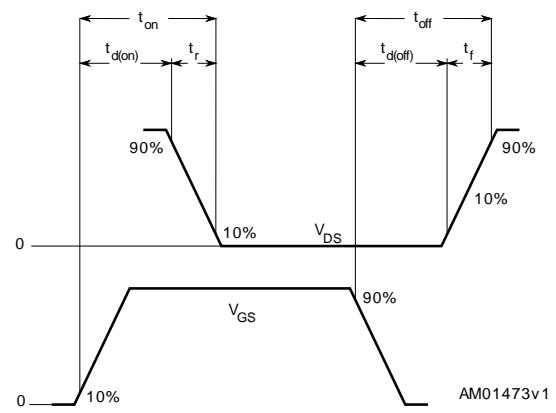
**Figure 17: Unclamped inductive load test circuit**



**Figure 18: Unclamped inductive waveform**



**Figure 19: Switching time waveform**

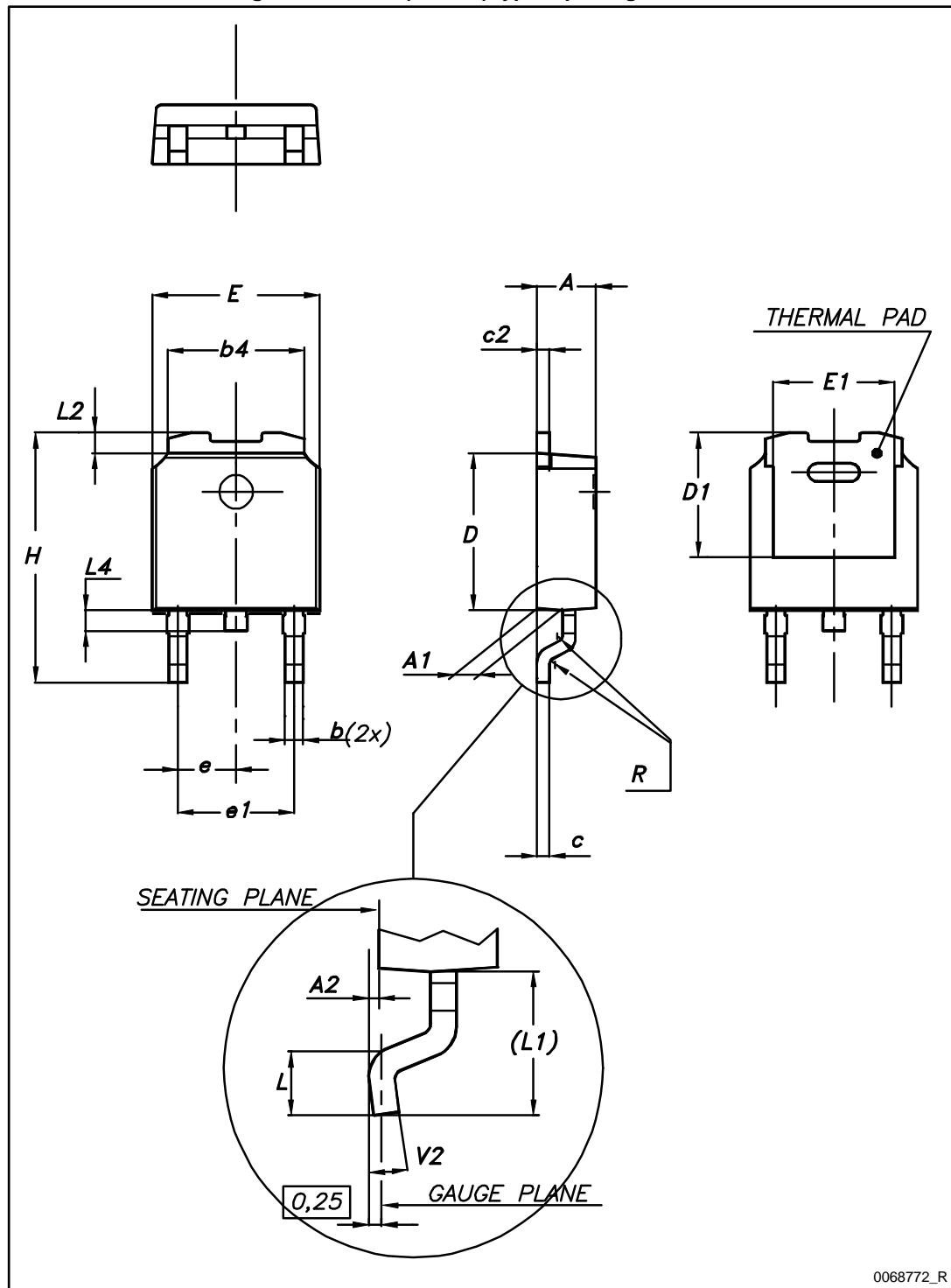


## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com).  
ECOPACK® is an ST trademark.

## 4.1 DPAK package information

Figure 20: DPAK (TO-252) type A package outline

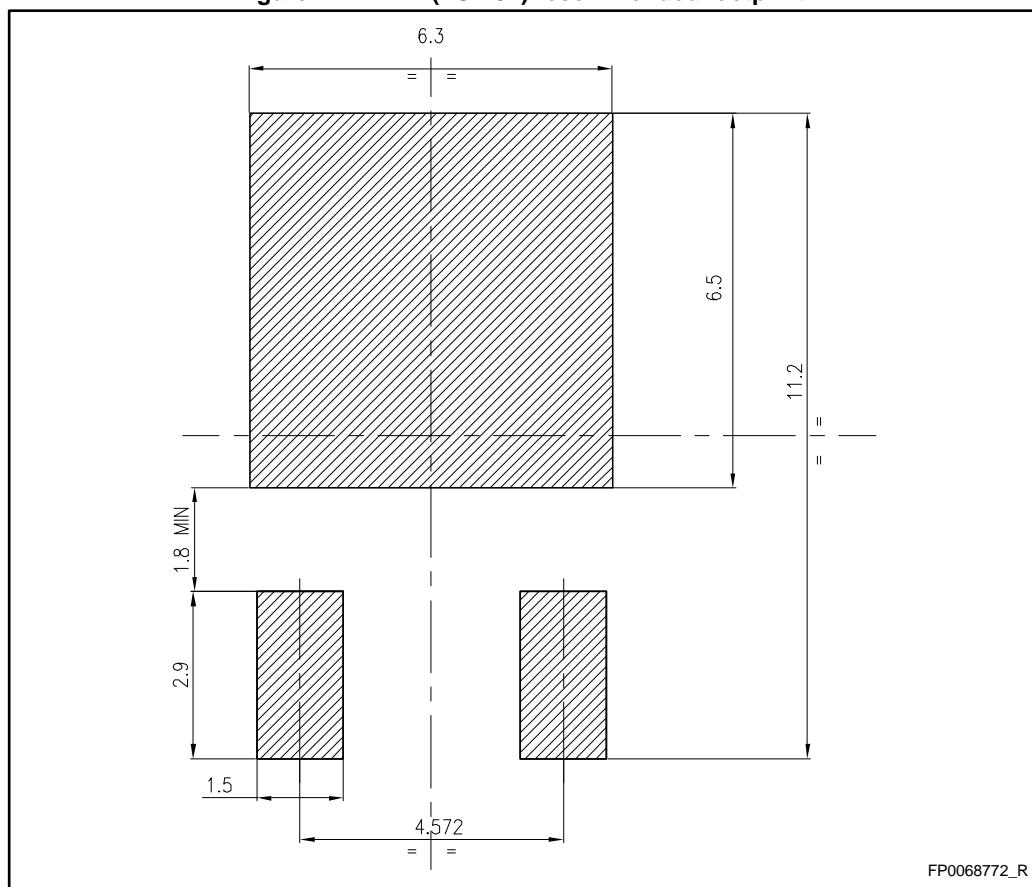


0068772\_R

**Table 9: DPAK (TO-252) type A mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
e		2.28	
e1	4.40		4.60
H	9.35		10.10
L	1.00		1.50
L1		2.80	
L2		0.80	
L4	0.60		1.00
R		0.20	
V2	0°		8°

Figure 21: DPAK (TO-252) recommended footprint



All dimensions are in mm



## 4.2 Packing information

Figure 22: Tape for DPAK (TO-252)

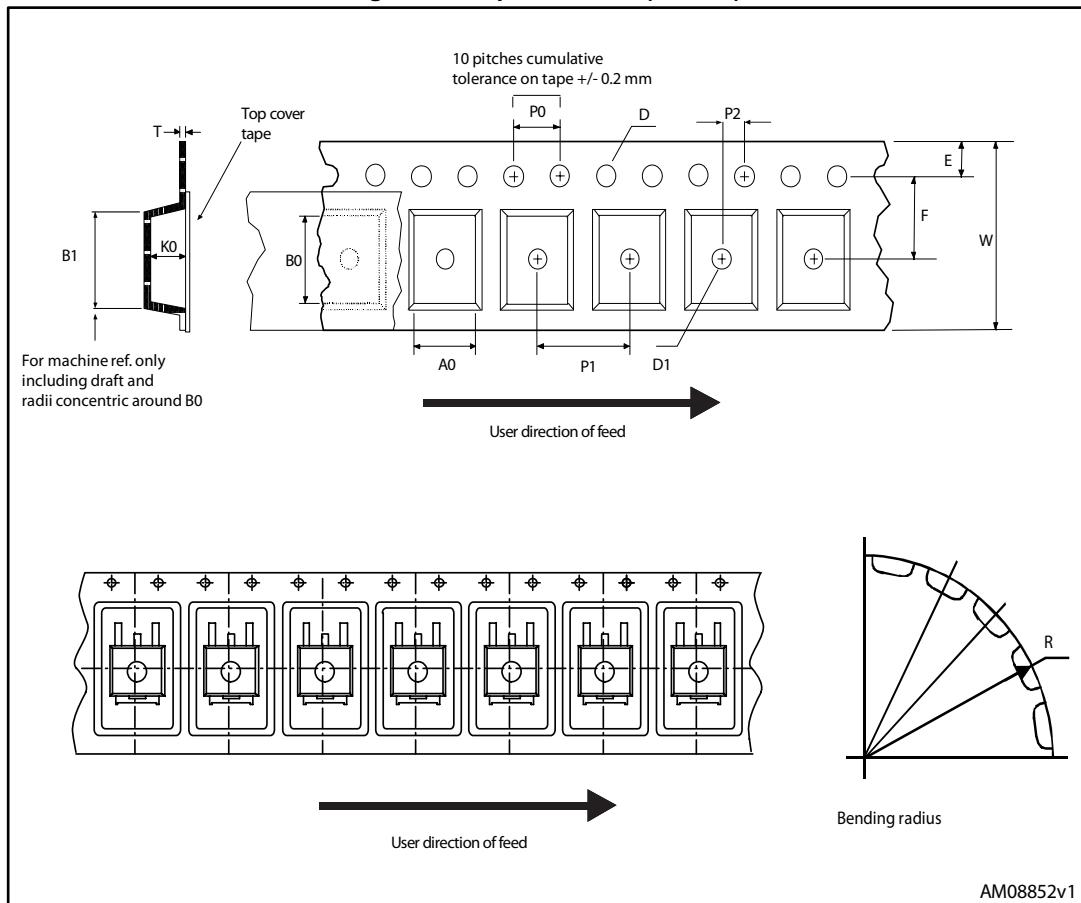


Figure 23: Reel for DPAK (TO-252)

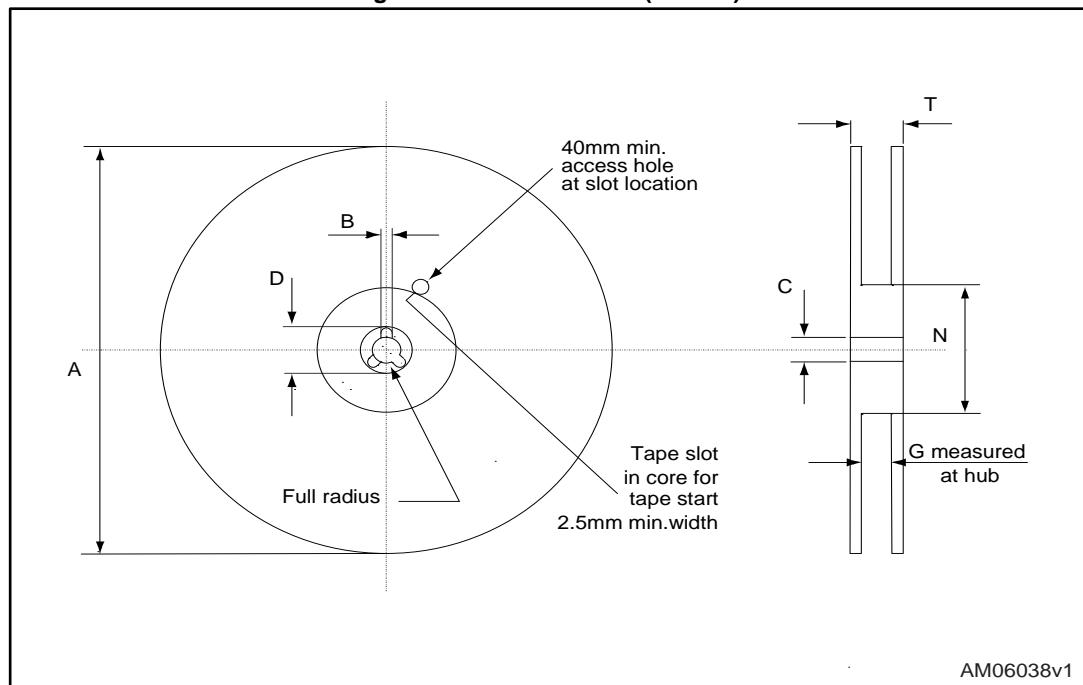


Table 10: DPAK (TO-252) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.		2500
P1	7.9	8.1	Bulk qty.		2500
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

## 5 Revision history

**Table 11: Document revision history**

Date	Revision	Changes
10-Mar-2015	1	Initial release.
23-Apr-2015	2	Document status promoted to 'Production data'.

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